Laser Inertial Fusion Dry-Wall Materials Exposure to X-rays and Ions*

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Outline of Presentation

- IFE Threat Spectra: RHEPP-1 can simulate ion threat to first wall
- Description of RHEPP-1 and and Heating Cycle
- W and W25Re:

Conclusions

Roughening as indicator of fatigue/stress Powder Met W form is worst for roughening Surface is raised, with possible exfoliation and deep stress cracking Evolved effects take hundreds of pulses to develop

Graphite/Carbon Composites:

Sublimation loss may be main problem – physical sputtering?

- 'Engineered' Materials as an alternative to flat wall
 - Carbon fiber 'Velvet

W/Tac and W/HfC 'Foams'

Plasma-sprayed W







Laser IFE Direct Drive Threat Spectra



Simulation: Thermal Power to Wall from 154 MJ Yield Wall Radius: 6.5 m

- For Direct-drive Laser IFE: 1-2% x-rays 30% ions (50-50 fusion and 'debris) ~70% neutrons
- lons: several MeV, ~ 0.5 μsec each, 8-20 J/cm² fluence
- X-rays: ~ 1 J/cm², up to 10 keV energies
- RHEPP-1: 800 keV He, higher for N⁺², 100-300 ns pulsewidth
- RHEPP-1 energy delivery too short, but otherwise good fidelity with reactor ion threat





Goals (for each material): examine net ablation to validate codes find threshold for ablation understand roughening find threshold for roughening





Pulsed Power Sciences, Sandia National Laboratories

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Single-pulse Z data shows no melting below 1.3 J/cm²







1.3 J/cm²
 2 m kimfoil
 2.5 m Be
 0.1 m Al
 No melting

2.3 J/cm² 2 m kimfoil 0.1 m Al 0.5 μ melting

19 J/cm² 2 μ melting

Unheated WDifficult to assess roughening with Z samples





RHEPP-1 combines Repetitive High Energy Pulse Power with a robust and versatile ion source: MAP



Left: Marx tank with pulse-forming line Right: 4-Stage LIVA and treatment chamber







The MAP (Magnetically Confined Anode Plasma) Ion Source is used for surface modification experiments on RHEPP-1



- 600-800 kV
- < 250 A/cm²
- Beams from H, He, N₂, O₂, Ne, Ar, Xe, Kr, CH₄
- Overall treatment area ~ 100 cm²
- Diode vacuum
 ~ 10⁻⁵ Torr







Nitrogen injection into MAP produces 3-component beam of mostly N++, N+



- Beam predominantly N++ and N+ after small proton pulse at front
- Peak voltage = 850 kV
 Peak current density (total) ~145 A/cm²
- Total fluence = 7.9 J/cm² will ablate almost all materials
- Total pulse width ~ 200 ns
- Ion range (TRIM):
 N+ 0.9 μm, N++ 1.2 μm
- Oxygen, Neon beams similar







Geometry for extended exposure series



- Photo shows plate with heated samples on right, unheated strips on left
- Samples shot 200X or 400X, Ra measured by 1-D Dektak, then reloaded for another set, until maximum is reached
- SEMS, WYCO 2-D profilometry after series completion







Tungsten roughening (Room Temperature): Detailed History of Reflectometer measurements



- Polished W exposed to N beam:
 0.6 <dose< 1.25 J/cm² (53 shots)
- Reflectometer photodiode signal (red) plotted as function of shot number (26081 -26127)
- Initial exposure at 1 J/cm² or less: photodiode remains above 20 mV
- Note progressive signal decrease after shot 26,112. Fluence is ~ 1.25 J/cm²





400 shot Map N shots on Tungsten (Room Temperature): Roughening only above threshold



- Polished W exposed to 400 shots N beam: 1.0 < fluence < 3.7 J/cm²
- Room Temp (RT) exposure
- Roughening occurs above 1.25 J/cm², consistent with single-shot reflectometer roughening threshold
- Powder Met Mo (one point at 2.5 J/cm²): roughness stays near unexposed value
- Above threshold, roughening is a severe function of fluence. Maximum R_a exceeds 22 μm, with P-V height above 70 μm
- Roughening threshold evidently lower for He beam







Trends in W roughening: Increases with fluence/shot number; PM W the worst



- Roughening increases ~ linearly with pulse number
- Roughening increases with fluence per pulse
- Very little surface relief happens until after 200 pulses
- 4.5 J/cm² is between melt and ablation for W
- He beam roughens more than N (black points)
- CVD, SingXtal (actually, everything) roughens less than PM W
- W Peak-Valley exceeds 70 µm at 600 shots
- Is W roughening reaching saturation?







Evolution of R_a Roughness at 4.0 J/cm²: WPowderMet, then everything else. Cu does NOT roughen



- 4 J/cm² is near or above ablation level for most metals shown
- Polished W and Mo are heated to 550 -600C
- W roughens beyond 10 µm R_a at 400-600 shots (only 600 taken)
- W25Re, Re reach 2 μ m R_a at 1000 shots, but Cu remains below 1 μ m
- Ti-2 (not shown) roughens steadily to 1000 shots
- W Peak-Valley exceeds 70 µm at 600 shots
- Is W roughening reaching saturation?



SEMs of PM W (non-melt): appears stress cracking starts, then exfoliation, forming valleys



All images 2000X



800 pulses

- Heated PM W (600C) exposed to N beam at ~ 1.5 J/cm² - peak temp ~ 3300K
- Rounded 'knobs' are actually high points. But does average surface height rise or fall?





SEMs of W25Re (short-melt): appears Similar but attentuated roughening compared to PM W



400 pulses

800 pulses

1200 pulses

All images 2000X

Heated W25Re (600C) exposed to N beam at ~ 1.5 J/cm² - peak temp ~ 3300K. Sample experienced short melt time







PM Tungsten after 1600 pulses (non-melting): Mostly mountains



Tungsten 1600 Pulses

- Heated/treated PM W examined with NEXIV laser interferometry
- Comprehensive line-out scan: max height 30 µm, min height < 10 µm compared to untreated
- Very deep microcracking not visible here







FIB-STEM of 1000-pulse W at 2.25 J/cm² (ave): No melting or recrystallization evident





Simulation results: Melt Depth: 0.2 μ m Melt Duration: 91 ns MaxTemp: 3752K (from 600C) R_a = 2.3 - 4.5 μ m



FIB-XTEM of 1000-pulse W at 2.25 J/cm² (ave): Deep horizontal/vertical cracking without melt



- Polished Powder Met W exposed to 100 shots N beam @ 2.25 J/cm² ave /pulse, ~ melting temperature at surface. No melt layer observed.
- 600°C exposure
- Sample cracking horizontally/vertically down to 10 µm depth
- Suspect fatigue-cracking



Comparison, treated W and W25Re, side view: 'Laminated' structure to 1mm depth on W, missing in W25Re



Photomicrographs, side view, 1600 pulses, surface temp to near-melt

Surface to near-middle (~ 0.8 mm) Surface to near-middle (~ 0.6 mm)

0.8 mm to ~ 1.5 mm

0.6 mm to ~ 1.2 mm





PM Tungsten

W25Re





Response of graphite to mixed H - C beam qualitatively confirms BUCKY predictions



- Mechanically polished pyrolitic graphite (PG), Poco, and 4D carbon composite weave exposed to 75 pulses/225 pulses of 70% C /30% H beam at doses of 1.9 to 5 J/cm²
- PG ablation threshold ~ 4 J/cm²
- Poco ablation threshold ~ 3 J/cm²
- Above threshold, rapid increase in ablated material per pulse with dose. Data scatter reflects uncertainty in dose
- Composite matrix ablates more than PG/Poco, fibers comparable (sample rough)







FMI-222 unheated CFC exposed to MAP N for 1000X at 1.6 J/cm²: Significant erosion of matrix









FMI-222 Fiber ends appear ablation-resistant; Matrix loss ~ 0.3 μm/pulse at 4.0 J/cm²:









W-coated Carbon 'Velvet' exposure to ions: 1.6 μ m W survives on sharp tips, 200 pulses at 6 J/cm²



Flat tips, W balls up on side





'Foam' (Ultramet) exposure to ions: W/TaC suffers erosional loss, W/HfC brittle failure



untreated, 50X



W/TaC, after 1200 pulses, 2500X

W/HfC, 800 pulses, 250X

SEMs: Thinner structures, better bonding may be necessary



Side view, W/TaC, after 800 pulses, showing **EXPANDED** height (left)



Plasma-sprayed W on Steel exposed to 400 Ion Pulses: Evidence of Mass-loss at low Fluence



454 W on Steel

- Plasma-sprayed W on steel (unheated) exposed to 400 pulses MAP N at average 1.4 J/cm²
- SIM model prediction:3000K max for surface temp
- Interface in middle, exposed at bottom
 - Dektak measurements not definitive – both sides too rough
 - Images indicate mass loss from treated side







SIM 'ELM' simulation: 3 kV protons on 600°C W @ 40 A/cm² for 500 µsec (60 J/cm²)



 This simulates estimated ELM deposition in H Mode tokamak discharge: 10 MJ over 5 m² for 500 µsec

•Pure W at 600 °C initial temp

Constant flux of 3 kV protons at

40 A/cm² for 500 μsec

Peak temp < 2200K after 500 µsec

 Peak temp less than SIM prediction for 1000 shot series

•Temp gradient < IFE case. Will fatigue cracking still occur?







Summary

- Ion exposure forms key part of Laser IFE Direct Drive First-Wall Threat. RHEPP-1 beams can simulate this threat with good fidelity
- For W materials, most serious issue is roughening, evidently caused by thermomechanical stress. Stress cracking is followed by erosion or exfoliation of material. Stress cracks deepen with pulse number, and may reach deep into interior. This is true regardless of melt.
- W25Re develops this topology less severely than W. But, along with Ti and Mo, still shows this behavior. Surface melting does not smooth the roughening, unless vaporization threshold is reached.
- Engineered materials such as 'Velvet' or 'Foam' may be an alternative surface design
- These results are relevant to MFE W exposure due to Type I ELMs



